



U.S. Patent Documents

Examiner Initials	Document No.	Date	Name	Class Subclass	Filing Date If Approp.
4P 4P	6,274,972 B1 2002/0030640 A1	8/01 3/02	Mitsutake et al Nomura et al		

Foreign Patent Documents

Document No.	Date	Country	Class Subclass	Translation Yes No
7-29527	1/95	Japan		(abstract)
10-199455	7/98	Japan Abstract		
2000-208076	7/00	Japan		(abstract)
2001003201	1/01	Korean Abstract		
2001-101965	4/01	Japan		(abstract)
WO 02/05307	1/02	PCT/US01/16666		

Other Documents (including Author, Title, Date, Pertinent Pages, etc.)

Examiner

Maria Hilg

Date Considered

12/11/04

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Draw line through citation if not in conformance and not considered. Include copy of this form with next
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